

In the Claims:

The claims are as follows.

1. (Currently amended) A method of inserting a test point into a circuit design, comprising :

selecting a node in said circuit design;

determining a driver cell of said node;

selecting from a file, a replacement cell for said driver cell, said replacement cell having a different gate than a gate in said driver cell, said different gate of said replacement cell having the same function of type of logic gate as said logic gate of said driver cell ,said replacement cell having a test point function; and

replacing said driver cell in said circuit design with said replacement cell.

2. (Original) The method of claim 1 wherein said circuit design has signal propagation delay limits and the signal propagation delay of said circuit design with said replacement cell is within said signal propagation delay limits of said circuit design.

3. (Original) The method of claim 1, wherein said test point function of said replacement cell is a control to zero, control to one or observe function.

4. (Original) The method of claim 1, wherein said file is a replacement table.

5. (Original) The method of claim 1, wherein said file is the design library used to create said

circuit design.

6. (Currently amended) A method of inserting a test point into a circuit design, comprising :

selecting said test point to be inserted into said circuit design, said circuit design having signal propagation delay limits;

determining a driver cell of the test point;

selecting from a file, a replacement cell for said driver cell, said replacement cell having a different gate than a gate in said driver cell, said different gate of said replacement cell having the same function of type of logic gate as said logic gate of said driver cell, said replacement cell having a test point function;

determining the delay of said circuit design with said replacement cell; and

replacing said driver cell with said replacement cell if the delay of said circuit design with said replacement cell is within said signal propagation delay limits.

7. (Currently amended) The method of claim 6, further including :

determining the delay of said circuit design with said driver cell; and

applying a predetermined range to the delay of said circuit design with said driver cell to create said signal propagation limits.

8. (Original) The method of claim 6, wherein said test point function of said replacement cell is a control to zero, control to one or observe function.

9. (Original) The method of claim 6, wherein said file is a replacement table.

10. Currently amended) The method of claim 6, wherein said file is ~~the~~ a design library used to create said circuit design.

11. (Original) The method of claim 9, wherein said replacement table comprises:

a list of driver cells comprised of at least a portion of the gates in the design library used to create said circuit design;

a combination of each of said gates in said list of driver cells and a control to zero function;

a combination of each of said gates in said list of driver cells and a control to one function; and

a combination of each of said gates in said list of driver cells and an observe function.

12. (Currently amended) The method of claim 11, wherein said replacement table further comprises additional gates ~~in addition to gates in said design library~~ including:

one or more combinations of said additional gates not in said design library and a control to zero function;

one or more combinations of ~~a~~ said additional gates not in said design library and a control to one function; and

one or more combinations of ~~a~~ said additional gates not in said design library and an observe function.

13. (Currently amended) A method of inserting a test point into a circuit design, comprising :

selecting a test point to be inserted into said circuit design, said circuit design having signal propagation delay limits;

determining a driver cell of the test point;

selecting from a file, all potential replacement cells for said driver cell, said potential replacement cells having different gates than a gate in said driver cell, said different gates of having the same function of type of logic gate as said logic gate of said driver cell and said replacement cells having a test point function;

determining ~~the~~ a delay of said circuit design with each of said potential replacement cells;

adding to an accept list those potential replacement cells where the delay of said circuit design with said potential replacement cell is within said signal propagation delay limits;

selecting a replacement cell from said accept list; and

replacing said driver cell with said replacement cell.

14. (Original) The method of claim 13, further including :

determining the delay of said circuit design with said driver cell; and

applying a predetermined range to the delay of said circuit design with said driver to create said signal propagation limits.

15. (Currently amended) The method of claim 13, further including the step of:

performing an early and a late mode analysis of said circuit design with said driver cell to determine said signal propagation delay limits.

16. (Currently amended) The method of claim 13, wherein said test point function of said potential replacement cell is a control to zero, control to one or observe function.

17. (Original) The method of claim 13, wherein said file is a replacement table.

18. (Currently amended) The method of claim 13, wherein said file is ~~the~~ a design library used to create said circuit design.

19. (Original) The method of claim 17, wherein said replacement table comprises:

a list of driver cells comprised of at least a portion of the gates in the design library used to create said circuit design;

a combination of each of said gates in said list of driver cells and a control to zero function;

a combination of each of said gates in said list of driver cells and a control to one function; and

a combination of each of said gates in said list of driver cells and an observe function.

20. (Currently amended) The method of claim 19, wherein said replacement table further

comprises additional gates ~~in addition to gates in said design library~~ including:

one or more combinations of ~~a~~ said additional gates not in said design library and a control to zero function;

one or more combinations of ~~a~~ said additional gates not in said design library and a control to one function; and

one or more combinations of ~~a~~ said additional gates not in said design library and an observe function.

21. (Currently amended) The method of claim 13, wherein the step of selecting a replacement cell from said accept list comprises selecting the potential replacement cell resulting that will result in a circuit delay closest to the delay of the circuit design with the driver cell to be replaced.

22. (Currently amended) The method of claim 13, wherein the step of selecting a replacement cell from said accept list comprises selecting the potential replacement cell having ~~the a~~ a smallest layout area of all potential replacement cells in said accept list.

23. (Original) The method of claim 13, wherein the step of selecting a replacement cell from said accept list comprises selecting the potential replacement cell having the smallest power requirement.

24. (Original) The method of claim 13, wherein the step of selecting a replacement cell from said

accept list comprises selecting the potential replacement cell according to a user defined algorithm for combining the layout area and the power requirement of the potential replacement cell.

25. (New) The method of claim 1, wherein the step of selecting from a file, a replacement cell for said driver cell comprises selecting the potential replacement cell having the smallest power requirement.

26. (New) The method of claim 1, wherein the step of selecting from a file, a replacement cell for said driver cell comprises selecting the potential replacement cell according to a user defined algorithm for combining the layout area and the power requirement of the potential replacement cell.

27. (New) The method of claim 1, wherein the step of selecting from a file, a replacement cell for said driver cell comprises selecting the potential replacement cell having the smallest power requirement.

28. (New) The method of claim 1, wherein the step of selecting from a file, a replacement cell for said driver cell comprises selecting the potential replacement cell according to a user defined algorithm for combining the layout area and the power requirement of the potential replacement cell.